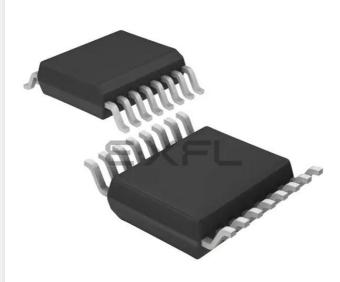
NXP USA Inc. - MC9S08PT16AVTG Datasheet





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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	20MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	LVD, POR, PWM, WDT
Number of I/O	14
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	256 x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	16-TSSOP
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08pt16avtg

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



- Input/Output
 - Up to 37 GPIOs including one output-only pin
 - One 8-bit keyboard interrupt module (KBI)
 - Two true open-drain output pins
 - Four, ultra-high current sink pins supporting 20 mA source/sink current
- Package options
 - 44-pin LQFP
 - 32-pin LQFP
 - 20-pin SOIC; 20-pin TSSOP
 - 16-pin TSSOP



1 Ordering parts

1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to freescale.com and perform a part number search for the following device numbers: PT16 and PT8.

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

MC 9 S08 PT AA (V) B CC

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
MC	Qualification status	MC = fully qualified, general market flow
9	Memory	• 9 = flash based
S08	Core	• S08 = 8-bit CPU
PT	Device family	• PT
AA	Approximate flash size in KB	 16 = 16 KB 8 = 8 KB
(V)	Mask set version	 (blank) = Any version A = Rev. 2 or later version, this is recommended for new design

Table continues on the next page ...

MC9S08PT16 Series Data Sheet, Rev. 3, 06/2015



Parameter Classification

Field	Description	Values
В	Operating temperature range (°C)	• V = -40 to 105
СС	Package designator	 LD = 44-LQFP LC = 32-LQFP TJ = 20-TSSOP WJ = 20-SOIC TG = 16-TSSOP

2.4 Example

This is an example part number:

MC9S08PT16VLD

3 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding, the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table 1. Parameter Classifications

Р	Those parameters are guaranteed during production testing on each individual device.
С	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
Т	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled "C" in the parameter tables where appropriate.



Nonswitching electrical specifications

6. Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If the positive injection current (V_{In} > V_{DD}) is higher than I_{DD}, the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Ensure that external V_{DD} load will shunt current higher than maximum injection current when the MCU is not consuming power, such as no system clock is present, or clock rate is very low (which would reduce overall power consumption).

Symbol	С	Descr	ription	Min	Тур	Мах	Unit
V _{POR}	D	POR re-arm	n voltage ^{1, 2}	1.5	1.75	2.0	V
V _{LVDH}	С	Falling low-venture for the shold - high = -		4.2	4.3	4.4	V
V _{LVW1H}	С	Falling low- voltage	Level 1 falling (LVWV = 00)	4.3	4.4	4.5	V
V _{LVW2H}	С	warning threshold - high range	Level 2 falling (LVWV = 01)	4.5	4.5	4.6	V
V _{LVW3H}	С		Level 3 falling (LVWV = 10)	4.6	4.6	4.7	V
V _{LVW4H}	С		Level 4 falling (LVWV = 11)	4.7	4.7	4.8	V
V _{HYSH}	С	High range detect/warnir	low-voltage ng hysteresis	—	100	_	mV
V _{LVDL}	С	Falling low-venture for the shold - low		2.56	2.61	2.66	V
V _{LVDW1L}	С	Falling low- voltage	Level 1 falling (LVWV = 00)	2.62	2.7	2.78	V
V _{LVDW2L}	С	warning threshold -	Level 2 falling (LVWV = 01)	2.72	2.8	2.88	V
V _{LVDW3L}	С	low range	Level 3 falling (LVWV = 10)	2.82	2.9	2.98	V
V _{LVDW4L}	С		Level 4 falling (LVWV = 11)	2.92	3.0	3.08	V
V _{HYSDL}	С	Low range low hyste	-voltage detect eresis	_	40	_	mV
V _{HYSWL}	С	Low range warning h	•	—	80		mV
V _{BG}	Р	Buffered ban	dgap output ⁴	1.14	1.16	1.18	V

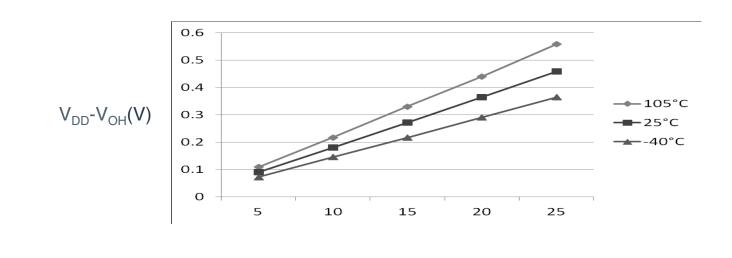
Table 3. LVD and POR Specification

1. Maximum is highest voltage that POR is guaranteed.

2. POR ramp time must be longer than 20us/V to get a stable startup.

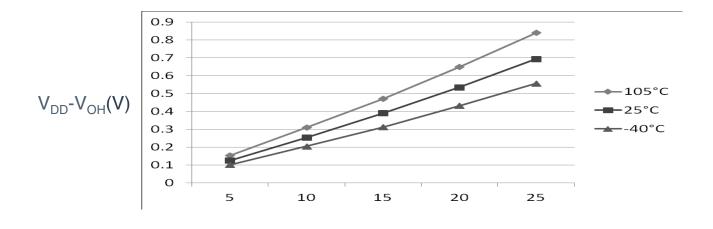
- 3. Rising thresholds are falling threshold + hysteresis.
- 4. Voltage factory trimmed at $V_{DD} = 5.0 \text{ V}$, Temp = 25 °C





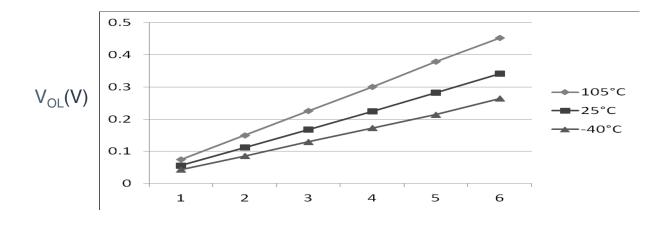
I_{OH}(mA)

Figure 3. Typical I_{OH} Vs. V_{DD} - V_{OH} (high drive strength) (V_{DD} = 5 V)



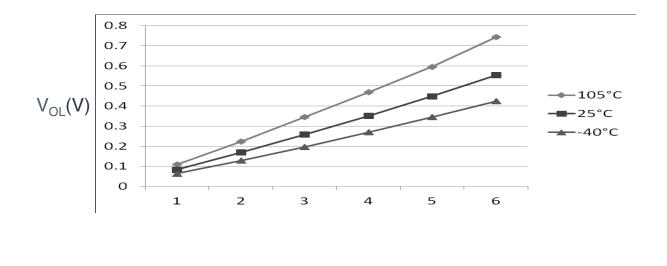
 $I_{OH}(mA)$ Figure 4. Typical I_{OH} Vs. V_{DD}-V_{OH} (high drive strength) (V_{DD} = 3 V)





I_{OL}(mA)

Figure 5. Typical I_{OL} Vs. V_{OL} (standard drive strength) (V_{DD} = 5 V)



I_{OL}(mA)

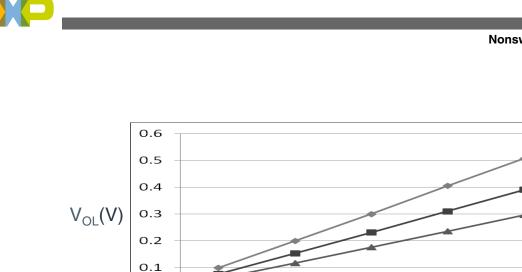
Figure 6. Typical I_{OL} Vs. V_{OL} (standard drive strength) (V_{DD} = 3 V)



105°C

25°C

-40°C



10

0

5

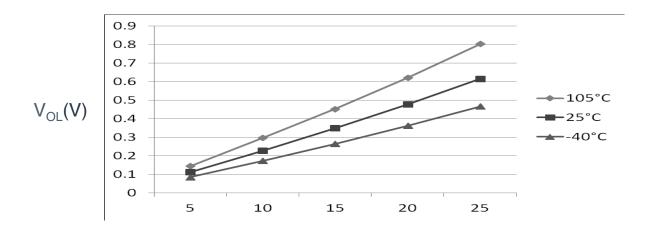
I_{OL}(mA)

Figure 7. Typical I_{OL} Vs. V_{OL} (high drive strength) (V_{DD} = 5 V)

15

20

25



I_{OL}(mA)

Figure 8. Typical I_{OL} Vs. V_{OL} (high drive strength) (V_{DD} = 3 V)



5.1.2 Supply current characteristics

This section includes information about power supply current in various operating modes.

Num	С	Parameter	Symbol	Bus Freq	V _{DD} (V)	Typical ¹	Max	Unit	Temp
1	С	Run supply current FEI	RI _{DD}	20 MHz	5	7.60	—	mA	-40 to 105 °C
	С	mode, all modules on; run from flash		10 MHz		4.65	—		
		nom nasn		1 MHz		1.90	—		
	С			20 MHz	3	7.05	—		
	С			10 MHz		4.40	—		
				1 MHz		1.85	—		
2	С	Run supply current FEI	RI _{DD}	20 MHz	5	5.88	—	mA	-40 to 105 °C
	С	mode, all modules off & gated; run from flash		10 MHz		3.70	—		
		gated, full north hash		1 MHz		1.85	_		
	С			20 MHz	3	5.35	_		
	С			10 MHz		3.42	—	1	
				1 MHz		1.80	_		
3	Р	Run supply current FBE	RI _{DD}	20 MHz	5	10.9	14.0	mA	-40 to 105 °C
	С	mode, all modules on; run from RAM		10 MHz		6.10	—		
				1 MHz		1.69	_		
	С			20 MHz	3	8.18	_		
				10 MHz		5.14	_		
				1 MHz		1.44	_		
4	Р	Run supply current FBE	RI _{DD}	20 MHz	5	8.50	13.0	mA	-40 to 105 °C
	С	mode, all modules off & gated; run from RAM		10 MHz		5.07	—		
		gated, full non fixin		1 MHz		1.59	_		
	С			20 MHz	3	6.11	_		
				10 MHz		4.10	—		
				1 MHz		1.34	_		
5	С	Wait mode current FEI	WI _{DD}	20 MHz	5	5.95	—	mA	-40 to 105 °C
		mode, all modules on		10 MHz		3.50	_		
				1 MHz		1.24	_		
	С			20 MHz	3	5.45	_		
				10 MHz		3.25	_		
				1 MHz		1.20	_		
6	С	Stop3 mode supply	S3I _{DD}	—	5	4.6	_	μA	-40 to 105 °C
	С	current no clocks active (except 1kHz LPO clock) ^{2, 3}			3	4.5	—		-40 to 105 °C
7	С	ADC adder to stop3		_	5	40		μA	-40 to 105 °C

Table 4. Supply current characteristics

Table continues on the next page ...



Num	С	Parameter	Symbol	Bus Freq	V _{DD} (V)	Typical ¹	Max	Unit	Temp
	С	ADLPC = 1			3	39	_		
		ADLSMP = 1							
		ADCO = 1							
		MODE = 10B							
		ADICLK = 11B							
8	С	TSI adder to stop3 ⁴	—	_	5	121	—	μA	-40 to 105 °C
	С	PS = 010B			3	120	—		
		NSCN = 0x0F							
		EXTCHRG = 0							
		REFCHRG = 0							
		DVOLT = 01B							
9	С	LVD adder to stop3 ⁵	—	_	5	128		μA	-40 to 105 °C
	С				3	124			

Table 4. Supply current characteristics (continued)

1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.

2. RTC adder cause <1 μA I_{DD} increase typically, RTC clock source is 1kHz LPO clock.

3. ACMP adder cause <10 μ A I_{DD} increase typically.

4. The current varies with TSI configuration and capacity of touch electrode. Please refer to TSI electrical specifications.

5. LVD is periodically woken up from stop3 by 5% duty cycle. The period is equal to or less than 2 ms.

5.1.3 EMC performance

Electromagnetic compatibility (EMC) performance is highly dependent on the environment in which the MCU resides. Board design and layout, circuit topology choices, location and characteristics of external components as well as MCU software operation all play a significant role in EMC performance. The system designer should consult Freescale applications notes such as AN2321, AN1050, AN1263, AN2764, and AN1259 for advice and guidance specifically targeted at optimizing EMC performance.

5.1.3.1 EMC radiated emissions operating behaviors Table 5. EMC radiated emissions operating behaviors for 44-pin LQFP

 Table 5. EMC radiated emissions operating behaviors for 44-pin L0 package

Symbol	Description	Frequency band (MHz)	Тур.	Unit	Notes
V _{RE1}	Radiated emissions voltage, band 1	0.15–50	8	dBµV	1, 2
V _{RE2}	Radiated emissions voltage, band 2	50–150	8	dBµV	
V _{RE3}	Radiated emissions voltage, band 3	150–500	8	dBµV	
V _{RE4}	Radiated emissions voltage, band 4	500–1000	5	dBµV	
V_{RE_IEC}	IEC level	0.15–1000	Ν	—	2, 3



switching specifications

- Determined according to IEC Standard 61967-1, Integrated Circuits Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 1: General Conditions and Definitions and IEC Standard 61967-2, Integrated Circuits - Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 2: Measurement of Radiated Emissions – TEM Cell and Wideband TEM Cell Method. Measurements were made while the microcontroller was running basic application code. The reported emission level is the value of the maximum measured emission, rounded up to the next whole number, from among the measured orientations in each frequency range.
- 2. V_{DD} = 5.0 V, T_A = 25 °C, f_{OSC} = 10 MHz (crystal), f_{SYS} = 20 MHz, f_{BUS} = 20 MHz
- 3. Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions TEM Cell and Wideband TEM Cell Method

5.2 Switching specifications

5.2.1 Control timing

Num	С	Rating		Symbol	Min	Typical ¹	Max	Unit
1	Р	Bus frequency $(t_{cyc} = 1/f_{Bus})$		f _{Bus}	DC	—	20	MHz
2	С	Internal low power oscillato	r frequency	f _{LPO}	—	1.0	_	KHz
3	D	External reset pulse width ²		t _{extrst}	1.5 ×	—	—	ns
					t _{cyc}			
4	D	Reset low drive		t _{rstdrv}	$34 \times t_{cyc}$	—	_	ns
5	D	BKGD/MS setup time after issuing background debug force reset to enter user or BDM modes		t _{MSSU}	500	_	_	ns
6	D	BKGD/MS hold time after issuing background debug force reset to enter user or BDM modes ³		t _{MSH}	100	—	—	ns
7	D	IRQ pulse width	Asynchronous path ²	t _{ILIH}	100	_	_	ns
	D		Synchronous path ⁴	t _{IHIL}	$1.5 \times t_{cyc}$	—	—	ns
8	D	Keyboard interrupt pulse width	Asynchronous path ²	t _{ILIH}	100	_	_	ns
	D		Synchronous path	t _{IHIL}	1.5 × t _{cyc}	—	_	ns
9	С	Port rise and fall time -	—	t _{Rise}	—	10.2	—	ns
	С	standard drive strength (load = 50 pF) ⁵		t _{Fall}	_	9.5	_	ns
	С	Port rise and fall time -	_	t _{Rise}	—	5.4	—	ns
	С	high drive strength (load = 50 pF) ⁵		t _{Fall}	—	4.6	—	ns

Table 6. Control timing

1. Typical values are based on characterization data at V_{DD} = 5.0 V, 25 °C unless otherwise stated.

- 2. This is the shortest pulse that is guaranteed to be recognized as a reset pin request.
- To enter BDM mode following a POR, BKGD/MS must be held low during the powerup and for a hold time of t_{MSH} after V_{DD} rises above V_{LVD}.
- 4. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In stop mode, the synchronizer is bypassed so shorter pulses can be recognized.
- 5. Timing is shown with respect to 20% V_{DD} and 80% V_{DD} levels. Temperature range -40 °C to 105 °C.



Switching specifications

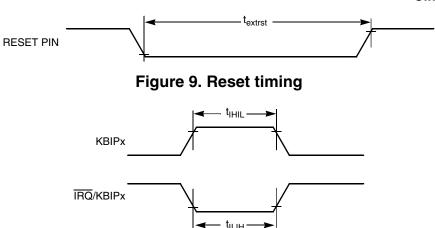


Figure 10. IRQ/KBIPx timing

5.2.2 Debug trace timing specifications Table 7. Debug trace operating behaviors

Symbol	Description	Min.	Max.	Unit
t _{cyc}	Clock period	Frequency dependent		MHz
t _{wl} Low pulse width		2		ns
t _{wh}	High pulse width	2		ns
t _r	Clock and data rise time	—	3	ns
t _f	Clock and data fall time	—	3	ns
t _s Data setup		3	—	ns
t _h	Data hold	2	—	ns

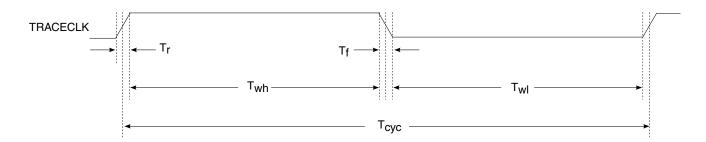


Figure 11. TRACE_CLKOUT specifications

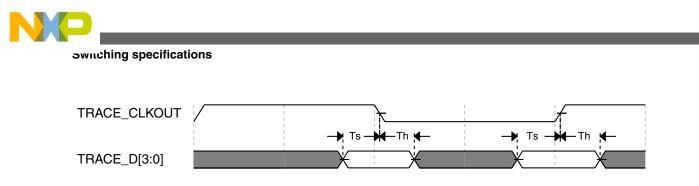


Figure 12. Trace data specifications

5.2.3 FTM module timing

Synchronizer circuits determine the shortest input pulses that can be recognized or the fastest clock that can be used as the optional external source to the timer counter. These synchronizers operate from the current bus rate clock.

No.	С	Function	Symbol	Min	Max	Unit
1	D	External clock frequency	f _{TCLK}	0	f _{Bus} /4	Hz
2	D	External clock period	t _{TCLK}	4	—	t _{cyc}
3	D	External clock high time	t _{clkh}	1.5	—	t _{cyc}
4	D	External clock low time	t _{clkl}	1.5	_	t _{cyc}
5	D	Input capture pulse width	t _{ICPW}	1.5	_	t _{cyc}

Table 8. FTM input timing

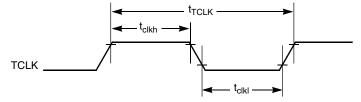


Figure 13. Timer external clock

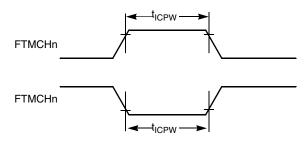


Figure 14. Timer input capture pulse



5.3 Thermal specifications

5.3.1 Thermal characteristics

This section provides information about operating temperature range, power dissipation, and package thermal resistance. Power dissipation on I/O pins is usually small compared to the power dissipation in on-chip logic and voltage regulator circuits, and it is user-determined rather than being controlled by the MCU design. To take $P_{I/O}$ into account in power calculations, determine the difference between actual pin voltage and V_{SS} or V_{DD} and multiply by the pin current for each I/O pin. Except in cases of unusually high pin current (heavy loads), the difference between pin voltage and V_{SS} or V_{DD} will be very small.

Rating	Symbol	Value	Unit
Operating temperature range (packaged)	T _A ¹	T_L to T_H -40 to 105	°C
Junction temperature range	TJ	-40 to 150	°C
	Thermal resistance	e single-layer board	
44-pin LQFP	R _{θJA}	76	°C/W
32-pin LQFP	R _{θJA}	88	°C/W
20-pin SOIC	R _{θJA}	82	°C/W
20-pin TSSOP	R _{θJA}	116	°C/W
16-pin TSSOP	R _{θJA}	130	°C/W
	Thermal resistant	ce four-layer board	
44-pin LQFP	R _{θJA}	54	°C/W
32-pin LQFP	R _{θJA}	59	°C/W
20-pin SOIC	R _{θJA}	54	°C/W
20-pin TSSOP	R _{θJA}	76	°C/W
16-pin TSSOP	R _{θJA}	87	°C/W

Table 9. Thermal characteristics

1. Maximum T_A can be exceeded only if the user ensures that T_J does not exceed the maximum. The simplest method to determine T_J is: $T_J = T_A + R_{\theta JA} x$ chip power dissipation.

6 Peripheral operating requirements and behaviors



Table 10. XOSC and ICS specifications (temperature range = -40 to 105 °C ambient) (continued)

Nur	n C	Characteristic	Symbol	Min	Typical ¹	Мах	Unit
13	С	Long term jitter of DCO output clock (averaged over 2 ms interval) ⁸	C _{Jitter}	_	0.02	0.2	%f _{dco}

- 1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.
- When ICS is configured for FEE or FBE mode, input clock source must be divisible using RDIV to within the range of 31.25 kHz to 39.0625 kHz.
- 3. See crystal or resonator manufacturer's recommendation.
- Load capacitors (C₁,C₂), feedback resistor (R_F) and series resistor (R_S) are incorporated internally when RANGE = HGO = 0.
- 5. This parameter is characterized and not tested on each device.
- 6. Proper PC board layout procedures must be followed to achieve specifications.
- This specification applies to any time the FLL reference source or reference divider is changed, trim value changed, or changing from FLL disabled (FBELP, FBILP) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
- Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{Bus}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the FLL circuitry via V_{DD} and V_{SS} and variation in crystal oscillator frequency increase the C_{Jitter} percentage for a given interval.

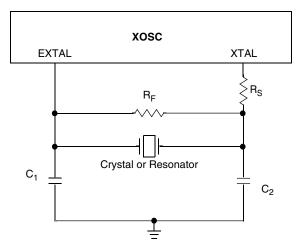


Figure 15. Typical crystal or resonator circuit

6.2 NVM specifications

This section provides details about program/erase times and program/erase endurance for the flash and EEPROM memories.

С	Characteristic	Symbol	Min ¹	Typical ²	Max ³	Unit ⁴
D	Supply voltage for program/erase -40 °C to 105 °C	V _{prog/erase}	2.7	—	5.5	V
D	Supply voltage for read operation	V _{Read}	2.7		5.5	V

Table 11. Flash characteristics

Table continues on the next page...

MC9S08PT16 Series Data Sheet, Rev. 3, 06/2015



С	Characteristic	Symbol	Min ¹	Typical ²	Max ³	Unit ⁴
D	NVM Bus frequency	f _{NVMBUS}	1	—	25	MHz
D	NVM Operating frequency	f _{NVMOP}	0.8	1	1.05	MHz
D	Erase Verify All Blocks	t _{VFYALL}	_	_	17338	t _{cyc}
D	Erase Verify Flash Block	t _{RD1BLK}	—	—	16913	t _{cyc}
D	Erase Verify EEPROM Block	t _{RD1BLK}	—	_	810	t _{cyc}
D	Erase Verify Flash Section	t _{RD1SEC}	_	_	484	t _{cyc}
D	Erase Verify EEPROM Section	t _{DRD1SEC}	_	—	555	t _{cyc}
D	Read Once	t _{RDONCE}	_	_	450	t _{cyc}
D	Program Flash (2 word)	t _{PGM2}	0.12	0.12	0.29	ms
D	Program Flash (4 word)	t _{PGM4}	0.20	0.21	0.46	ms
D	Program Once	t _{PGMONCE}	0.20	0.21	0.21	ms
D	Program EEPROM (1 Byte)	t _{DPGM1}	0.10	0.10	0.27	ms
D	Program EEPROM (2 Byte)	t _{DPGM2}	0.17	0.18	0.43	ms
D	Program EEPROM (3 Byte)	t _{DPGM3}	0.25	0.26	0.60	ms
D	Program EEPROM (4 Byte)	t _{DPGM4}	0.32	0.33	0.77	ms
D	Erase All Blocks	t _{ERSALL}	96.01	100.78	101.49	ms
D	Erase Flash Block	t _{ERSBLK}	95.98	100.75	101.44	ms
D	Erase Flash Sector	t _{ERSPG}	19.10	20.05	20.08	ms
D	Erase EEPROM Sector	t _{DERSPG}	4.81	5.05	20.57	ms
D	Unsecure Flash	t _{UNSECU}	96.01	100.78	101.48	ms
D	Verify Backdoor Access Key	t _{VFYKEY}	_	—	464	t _{cyc}
D	Set User Margin Level	t _{MLOADU}	_	_	407	t _{cyc}
С	FLASH Program/erase endurance T_L to T_H = -40 °C to 105 °C	n _{FLPE}	10 k	100 k		Cycles
С	EEPROM Program/erase endurance TL to TH = -40 °C to 105 °C	N _{FLPE}	50 k	500 k	_	Cycles
С	Data retention at an average junction temperature of T _{Javg} = 85°C after up to 10,000 program/erase cycles	t _{D_ret}	15	100		years

Table 11. Flash characteristics (continued)

1. Minimum times are based on maximum f_{NVMOP} and maximum f_{NVMBUS}

2. Typical times are based on typical f_{NVMOP} and maximum f_{NVMBUS}

3. Maximum times are based on typical f_{NVMOP} and typical f_{NVMBUS} plus aging

4. $t_{cyc} = 1 / f_{NVMBUS}$

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see the Memory section.



rempheral operating requirements and behaviors

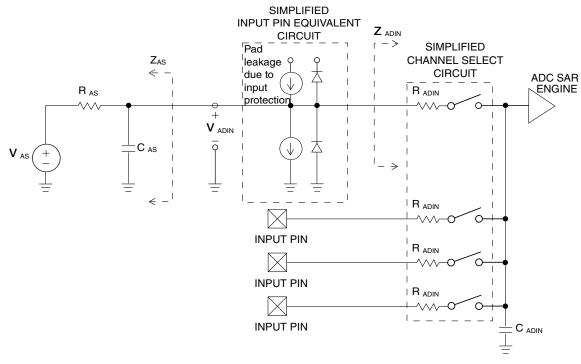


Figure 16. ADC input impedance equivalency diagram

Table 13.	12-bit ADC C	Characteristics	(V _{REFH} =	V _{DDA} , V _{REFL}	= V _{SSA})
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Characteristic	Conditions	С	Symb	Min	Typ ¹	Max	Unit
Supply current		Т	I _{DDA}	_	133	_	μA
ADLPC = 1							
ADLSMP = 1							
ADCO = 1							
Supply current		Т	I _{DDA}	—	218	—	μA
ADLPC = 1							
ADLSMP = 0							
ADCO = 1							
Supply current		Т	I _{DDA}	_	327	—	μA
ADLPC = 0							
ADLSMP = 1							
ADCO = 1							
Supply current		Т	I _{DDAD}	_	582	990	μA
ADLPC = 0							
ADLSMP = 0							
ADCO = 1							
Supply current	Stop, reset, module off	Т	I _{DDA}	-	0.011	1	μA
ADC asynchronous clock source	High speed (ADLPC = 0)	Р	f _{ADACK}	2	3.3	5	MHz

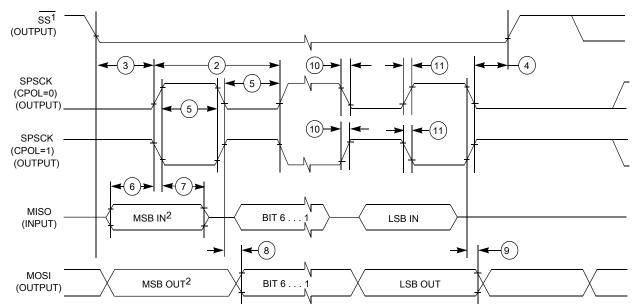
Table continues on the next page...



Peripheral operating requirements and behaviors

Nu m.	Symbol	Description	Min.	Max.	Unit	Comment
	t _{FI}	Fall time input				
11	t _{RO}	Rise time output	—	25	ns	—
	t _{FO}	Fall time output				

Table 15. SPI master mode timing (continued)



1. If configured as an output.

2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

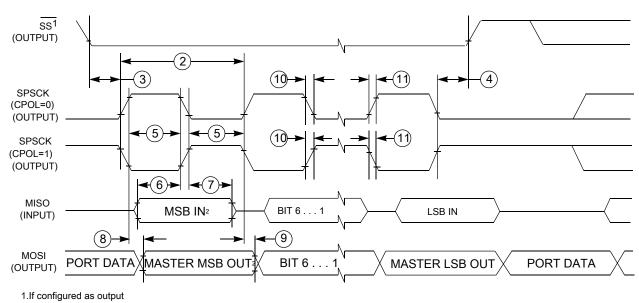


Figure 17. SPI master mode timing (CPHA=0)

2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 18. SPI master mode timing (CPHA=1)



	Pin	Number			Lowes	st Priority <> H	lighest	
44-LQFP	32-LQFP	20-TSSOP	16-TSSOP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
18	_	_	—	PTD5	_	—	_	—
19	13	11	—	PTC1	_	FTM2CH1	ADP9	TSI7
20	14	12		PTC0		FTM2CH0	ADP8	TSI6
21	15	13	9	PTB3	KBI0P7	MOSI0	ADP7	TSI5
22	16	14	10	PTB2	KBI0P6	SPSCK0	ADP6	TSI4
23	17	15	11	PTB1	KBI0P5	TXD0	ADP5	TSI3
24	18	16	12	PTB0	KBI0P4	RXD0	ADP4	TSI2
25	19		—	PTA7	_	FTM2FAULT2	ADP3	TSI1
26	20			PTA6		FTM2FAULT1	ADP2	TSI0
27	_	_	—	_	_	—	_	Vss
28	—	_	—		—	—	—	V _{DD}
29	_		—	PTD4	_	—	_	_
30	21	_	—	PTD3	_	—	_	TSI15
31	22	_	—	PTD2	—	—	—	TSI14
32	23	17	13	PTA3 ²	KBI0P3	TXD0	SCL	—
33	24	18	14	PTA2 ²	KBI0P2	RXD0	SDA	_
34	25	19	15	PTA1	KBI0P1	FTM0CH1	ACMP1	ADP1
35	26	20	16	PTA0	KBI0P0	FTM0CH0	ACMP0	ADP0
36	27	_	—	PTC7	_	TxD1	_	TSI13
37	28		—	PTC6	_	RxD1	_	TSI12
38	_		_	PTE2	_	MISO0	_	_
39	_	_	—	PTE1		MOSI0	_	—
40	—	—	—	PTE0	_	SPSCK0	_	—
41	29	_	—	PTC5	—	FTM0CH1	_	TSI11
42	30	_	—	PTC4	_	FTM0CH0	_	TSI10
43	31	1	1	PTA5	IRQ	TCLK0	—	RESET
44	32	2	2	PTA4	—	ACMPO	BKGD	MS

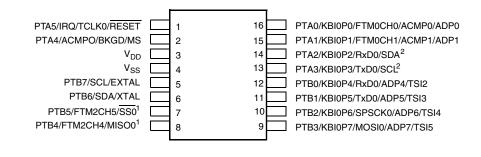
1. This is a high current drive pin when operated as output.

2. This is a true open-drain pin when operated as output.

Note

When an alternative function is first enabled, it is possible to get a spurious edge to the module. User software must clear any associated flags before interrupts are enabled. The table above illustrates the priority if multiple modules are enabled. The highest priority module will have control over the pin. Selecting a higher priority pin function with a lower priority function





Pins in **bold** are not available on less pin-count packages. 1. High source/sink current pins

2. True open drain pins

Figure 24. MC9S08PT16 16-pin TSSOP package

9 Revision history

The following table provides a revision history for this document.

Rev. No.	Date	Substantial Changes
1	7/2012	Initial public release
2	09/2014	 Updated V_{OH} and V_{OL} in DC characteristics Added footnote on the S3I_{DD} in Supply current characteristics Added EMC radiated emissions operating behaviors Updated the typical of f_{int_t} to 31.25 kHz and updated footnote to t_{Acquire} in External oscillator (XOSC) and ICS characteristics Updated the assumption for all the timing values in SPI switching specifications Updated the rating descriptions for t_{Rise} and t_{Fall} in Control timing Updated the part number format to add new field for new part numbers in Fields
3	06/2015	 Corrected the Min. of the t_{extrst} in Control timing Updated Thermal characteristics to add footnote to the T_A and removed redundant information.Updated the symbol of θ_{JA} to R_{θJA}.

Table 19. Revision history



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